

## FEATURES

**Latch-up proof**  
**5.5 pF off source capacitance**  
**52 pF off drain capacitance**  
**0.4 pC charge injection**  
**Low on resistance: 160  $\Omega$  typical**  
 **$\pm 9$  V to  $\pm 22$  V dual-supply operation**  
**9 V to 40 V single-supply operation**  
**48 V supply maximum ratings**  
**Fully specified at  $\pm 15$  V,  $\pm 20$  V,  $+12$  V, and  $+36$  V**  
 **$V_{SS}$  to  $V_{DD}$  analog signal range**  
**Human body model (HBM) ESD rating**  
**4 kV I/O port to supplies**  
**1 kV I/O port to I/O port**  
**4 kV all other pins**

## APPLICATIONS

**Automatic test equipment**  
**Data acquisition**  
**Instrumentation**  
**Avionics**  
**Audio and video switching**  
**Communication systems**

## GENERAL DESCRIPTION

The **ADG5208/ADG5209** are monolithic CMOS analog multiplexers comprising eight single channels and four differential channels, respectively. The **ADG5208** switches one of eight inputs to a common output, as determined by the 3-bit binary address lines, A0, A1, and A2. The **ADG5209** switches one of four differential inputs to a common differential output, as determined by the 2-bit binary address lines, A0 and A1.

An EN input on both devices enables or disables the device. When EN is disabled, all channels switch off. The ultralow capacitance and charge injection of these switches make them ideal solutions for data acquisition and sample-and-hold applications, where low glitch and fast settling are required. Fast switching speed coupled with high signal bandwidth make these devices suitable for video signal switching.

Each switch conducts equally well in both directions when on, and each switch has an input signal range that extends to the power supplies. In the off condition, signal levels up to the supplies are blocked.

## FUNCTIONAL BLOCK DIAGRAMS

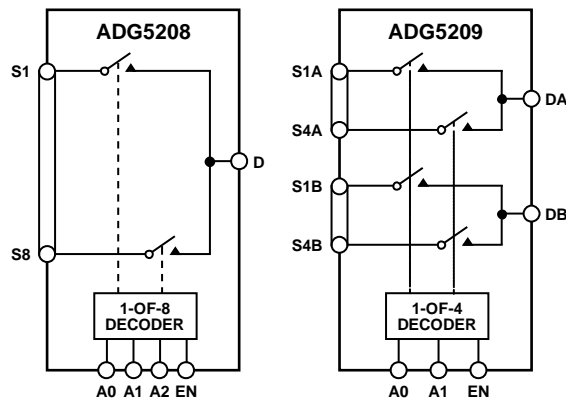


Figure 1.

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The **ADG5208/ADG5209** do not have  $V_L$  pins; instead, the logic power supply is generated internally by an on-chip voltage generator.

## PRODUCT HIGHLIGHTS

1. Trench Isolation Guards Against Latch-Up.  
A dielectric trench separates the P and N channel transistors to prevent latch-up even under severe overvoltage conditions.
2. 0.4 pC Charge Injection.
3. Dual-Supply Operation.  
For applications where the analog signal is bipolar, the **ADG5208/ADG5209** can be operated from dual supplies of up to  $\pm 22$  V.
4. Single-Supply Operation.  
For applications where the analog signal is unipolar, the **ADG5208/ADG5209** can be operated from a single rail power supply of up to 40 V.
5. 3 V Logic-Compatible Digital Inputs.  
 $V_{INH} = 2.0$  V,  $V_{INL} = 0.8$  V.
6. No  $V_L$  Logic Power Supply Required.

### Rev. A

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REVISION HISTORY

3/12—Rev. 0 to Rev. A	
Added 16-Lead LFCSP.....	Universal
Changes to Ordering Guide .....	22
7/11—Revision 0: Initial Version	

## SPECIFICATIONS

## ±15 V DUAL SUPPLY

$V_{DD} = +15\text{ V} \pm 10\%$ ,  $V_{SS} = -15\text{ V} \pm 10\%$ ,  $GND = 0\text{ V}$ , unless otherwise noted.

Table 1.

Parameter	25°C	−40°C to +85°C	−40°C to +125°C	Unit	Test Conditions/Comments
ANALOG SWITCH					
Analog Signal Range			V <sub>DD</sub> to V <sub>SS</sub>	V	
On Resistance, R <sub>ON</sub>	160 200	250	280	Ω typ Ω max	V <sub>S</sub> = ±10 V, I <sub>S</sub> = −1 mA; see Figure 28 V <sub>DD</sub> = +13.5 V, V <sub>SS</sub> = −13.5 V
On-Resistance Match Between Channels, ΔR <sub>ON</sub>	3.5			Ω typ	V <sub>S</sub> = ±10 V, I <sub>S</sub> = −1 mA
On-Resistance Flatness, R <sub>FLAT (ON)</sub>	8	9	10	Ω max	V <sub>S</sub> = ±10 V, I <sub>S</sub> = −1 mA
	40			Ω typ	
	50	65	70	Ω max	
LEAKAGE CURRENTS					
Source Off Leakage, I <sub>S</sub> (Off)	±0.005 ±0.1	±0.2	±0.4	nA typ nA max	V <sub>DD</sub> = +16.5 V, V <sub>SS</sub> = −16.5 V V <sub>S</sub> = ±10 V, V <sub>D</sub> = ∓ 10 V; see Figure 30
Drain Off Leakage, I <sub>D</sub> (Off)	±0.005 ±0.1	±0.4	±1.4	nA typ nA max	V <sub>S</sub> = ±10 V, V <sub>D</sub> = ∓ 10 V; see Figure 30
Channel On Leakage, I <sub>D</sub> (On), I <sub>S</sub> (On)	±0.01 ±0.2	±0.5	±1.4	nA typ nA max	V <sub>S</sub> = V <sub>D</sub> = ±10 V; see Figure 27
DIGITAL INPUTS					
Input High Voltage, V <sub>INH</sub>			2.0	V min	V <sub>IN</sub> = V <sub>GND</sub> or V <sub>DD</sub>
Input Low Voltage, V <sub>INL</sub>			0.8	V max	
Input Current, I <sub>INL</sub> or I <sub>INH</sub>	0.002		±0.1	μA typ μA max	
Digital Input Capacitance, C <sub>IN</sub>	3			pF typ	
DYNAMIC CHARACTERISTICS <sup>1</sup>					
Transition Time, t <sub>TRANSITION</sub>	170 205	245	275	ns typ ns max	R <sub>L</sub> = 300 Ω, C <sub>L</sub> = 35 pF V <sub>S</sub> = 10 V; see Figure 33
t <sub>ON</sub> (EN)	145 185	220	245	ns typ ns max	R <sub>L</sub> = 300 Ω, C <sub>L</sub> = 35 pF V <sub>S</sub> = 10 V; see Figure 35
t <sub>OFF</sub> (EN)	120 145	165	180	ns typ ns max	R <sub>L</sub> = 300 Ω, C <sub>L</sub> = 35 pF V <sub>S</sub> = 10 V; see Figure 35
Break-Before-Make Time Delay, t <sub>D</sub>	65		30	ns typ ns min	R <sub>L</sub> = 300 Ω, C <sub>L</sub> = 35 pF V <sub>S1</sub> = V <sub>S2</sub> = 10 V; see Figure 34
Charge Injection, Q <sub>INJ</sub>	0.4			pC typ	V <sub>S</sub> = 0 V, R <sub>S</sub> = 0 Ω, C <sub>L</sub> = 1 nF; see Figure 36
Off Isolation	−90			dB typ	R <sub>L</sub> = 50 Ω, C <sub>L</sub> = 5 pF, f = 1 MHz; see Figure 31
Channel-to-Channel Crosstalk	−90			dB typ	R <sub>L</sub> = 50 Ω, C <sub>L</sub> = 5 pF, f = 1 MHz; see Figure 29
−3 dB Bandwidth					R <sub>L</sub> = 50 Ω, C <sub>L</sub> = 5 pF; see Figure 32
ADG5208	54			MHz typ	
ADG5209	133			MHz typ	
Insertion Loss	−6.4			dB typ	R <sub>L</sub> = 50 Ω, C <sub>L</sub> = 5 pF, f = 1 MHz; see Figure 32
C <sub>S</sub> (Off)	5.5			pF typ	V <sub>S</sub> = 0 V, f = 1 MHz
C <sub>D</sub> (Off)					
ADG5208	52			pF typ	V <sub>S</sub> = 0 V, f = 1 MHz
ADG5209	26			pF typ	V <sub>S</sub> = 0 V, f = 1 MHz

Parameter	25°C	−40°C to +85°C	−40°C to +125°C	Unit	Test Conditions/Comments
$C_D$ (On), $C_S$ (On)					
ADG5208	58			pF typ	$V_S = 0\text{ V}$ , $f = 1\text{ MHz}$
ADG5209	31			pF typ	$V_S = 0\text{ V}$ , $f = 1\text{ MHz}$
POWER REQUIREMENTS					$V_{DD} = +16.5\text{ V}$ , $V_{SS} = -16.5\text{ V}$
$I_{DD}$	45			$\mu\text{A typ}$	Digital inputs = 0 V or $V_{DD}$
	55		70	$\mu\text{A max}$	
$I_{SS}$	0.001			$\mu\text{A typ}$	Digital inputs = 0 V or $V_{DD}$
			1	$\mu\text{A max}$	
$V_{DD}/V_{SS}$			$\pm 9/\pm 22$	V min/V max	GND = 0 V

<sup>1</sup> Guaranteed by design; not subject to production test.

## ±20 V DUAL SUPPLY

$V_{DD} = +20\text{ V} \pm 10\%$ ,  $V_{SS} = -20\text{ V} \pm 10\%$ , GND = 0 V, unless otherwise noted.

Table 2.

Parameter	25°C	−40°C to +85°C	−40°C to +125°C	Unit	Test Conditions/Comments
ANALOG SWITCH					
Analog Signal Range			$V_{DD}$ to $V_{SS}$	V	
On Resistance, $R_{ON}$	140			$\Omega$ typ	$V_S = \pm 15\text{ V}$ , $I_S = -1\text{ mA}$ ; see Figure 28
	160	200	230	$\Omega$ max	$V_{DD} = +18\text{ V}$ , $V_{SS} = -18\text{ V}$
On-Resistance Match Between Channels, $\Delta R_{ON}$	3.5			$\Omega$ typ	$V_S = \pm 15\text{ V}$ , $I_S = -1\text{ mA}$
	8	9	10	$\Omega$ max	
On-Resistance Flatness, $R_{FLAT(ON)}$	34			$\Omega$ typ	$V_S = \pm 15\text{ V}$ , $I_S = -1\text{ mA}$
	45	55	60	$\Omega$ max	
LEAKAGE CURRENTS					$V_{DD} = +22\text{ V}$ , $V_{SS} = -22\text{ V}$
Source Off Leakage, $I_S$ (Off)	$\pm 0.005$			nA typ	$V_S = \pm 15\text{ V}$ , $V_D = \mp 15\text{ V}$ ; see Figure 30
	$\pm 0.1$	$\pm 0.2$	$\pm 0.4$	nA max	
Drain Off Leakage, $I_D$ (Off)	$\pm 0.005$			nA typ	$V_S = \pm 15\text{ V}$ , $V_D = \mp 15\text{ V}$ ; see Figure 30
	$\pm 0.1$	$\pm 0.4$	$\pm 1.4$	nA max	
Channel On Leakage, $I_D$ (On), $I_S$ (On)	$\pm 0.01$			nA typ	$V_S = V_D = \pm 15\text{ V}$ ; see Figure 27
	$\pm 0.2$	$\pm 0.5$	$\pm 1.4$	nA max	
DIGITAL INPUTS					
Input High Voltage, $V_{INH}$			2.0	V min	
Input Low Voltage, $V_{INL}$			0.8	V max	
Input Current, $I_{INL}$ or $I_{INH}$	0.002			$\mu\text{A typ}$	$V_{IN} = V_{GND}$ or $V_{DD}$
			$\pm 0.1$	$\mu\text{A max}$	
Digital Input Capacitance, $C_{IN}$	3			pF typ	
DYNAMIC CHARACTERISTICS <sup>1</sup>					
Transition Time, $t_{TRANSITION}$	160			ns typ	$R_L = 300\ \Omega$ , $C_L = 35\text{ pF}$
	195	225	255	ns max	$V_S = 10\text{ V}$ ; see Figure 33
$t_{ON}$ (EN)	145			ns typ	$R_L = 300\ \Omega$ , $C_L = 35\text{ pF}$
	170	200	225	ns max	$V_S = 10\text{ V}$ ; see Figure 35
$t_{OFF}$ (EN)	120			ns typ	$R_L = 300\ \Omega$ , $C_L = 35\text{ pF}$
	140	155	170	ns max	$V_S = 10\text{ V}$ ; see Figure 35
Break-Before-Make Time Delay, $t_D$	55			ns typ	$R_L = 300\ \Omega$ , $C_L = 35\text{ pF}$
			30	ns min	$V_{S1} = V_{S2} = 10\text{ V}$ ; see Figure 34
Charge Injection, $Q_{INJ}$	0.3			pC typ	$V_S = 0\text{ V}$ , $R_S = 0\ \Omega$ , $C_L = 1\text{ nF}$ ; see Figure 36
Off Isolation	−90			dB typ	$R_L = 50\ \Omega$ , $C_L = 5\text{ pF}$ , $f = 1\text{ MHz}$ ; see Figure 31
Channel-to-Channel Crosstalk	−90			dB typ	$R_L = 50\ \Omega$ , $C_L = 5\text{ pF}$ , $f = 1\text{ MHz}$ ; see Figure 29

Parameter	25°C	−40°C to +85°C	−40°C to +125°C	Unit	Test Conditions/Comments
−3 dB Bandwidth					$R_L = 50\ \Omega$ , $C_L = 5\ \text{pF}$ ; see Figure 32
ADG5208	60			MHz typ	
ADG5209	130			MHz typ	
Insertion Loss	−5.6			dB typ	$R_L = 50\ \Omega$ , $C_L = 5\ \text{pF}$ , $f = 1\ \text{MHz}$ ; see Figure 32
$C_S$ (Off)	5.5			pF typ	$V_S = 0\ \text{V}$ , $f = 1\ \text{MHz}$
$C_D$ (Off)					
ADG5208	51			pF typ	$V_S = 0\ \text{V}$ , $f = 1\ \text{MHz}$
ADG5209	26			pF typ	$V_S = 0\ \text{V}$ , $f = 1\ \text{MHz}$
$C_D$ (On), $C_S$ (On)					
ADG5208	57			pF typ	$V_S = 0\ \text{V}$ , $f = 1\ \text{MHz}$
ADG5209	31			pF typ	$V_S = 0\ \text{V}$ , $f = 1\ \text{MHz}$
<b>POWER REQUIREMENTS</b>					
$I_{DD}$	50			$\mu\text{A}$ typ	$V_{DD} = +22\ \text{V}$ , $V_{SS} = -22\ \text{V}$ Digital inputs = 0 V or $V_{DD}$
	70		110	$\mu\text{A}$ max	
$I_{SS}$	0.001			$\mu\text{A}$ typ	Digital inputs = 0 V or $V_{DD}$
			1	$\mu\text{A}$ max	
$V_{DD}/V_{SS}$			$\pm 9/\pm 22$	V min/V max	GND = 0 V

<sup>1</sup> Guaranteed by design; not subject to production test.

## 12 V SINGLE SUPPLY

$V_{DD} = 12\ \text{V} \pm 10\%$ ,  $V_{SS} = 0\ \text{V}$ , GND = 0 V, unless otherwise noted.

Table 3.

Parameter	25°C	−40°C to +85°C	−40°C to +125°C	Unit	Test Conditions/Comments
<b>ANALOG SWITCH</b>					
Analog Signal Range			0 V to $V_{DD}$	V	
On Resistance, $R_{ON}$	350			$\Omega$ typ	$V_S = 0\ \text{V}$ to 10 V, $I_S = -1\ \text{mA}$ ; see Figure 28
	500	610	700	$\Omega$ max	$V_{DD} = 10.8\ \text{V}$ , $V_{SS} = 0\ \text{V}$
On-Resistance Match Between Channels, $\Delta R_{ON}$	5			$\Omega$ typ	$V_S = 0\ \text{V}$ to 10 V, $I_S = -1\ \text{mA}$
	20	22	24	$\Omega$ max	
On-Resistance Flatness, $R_{FLAT(ON)}$	160			$\Omega$ typ	$V_S = 0\ \text{V}$ to 10 V, $I_S = -1\ \text{mA}$
	280	335	370	$\Omega$ max	
<b>LEAKAGE CURRENTS</b>					
Source Off Leakage, $I_S$ (Off)	$\pm 0.005$			nA typ	$V_{DD} = 13.2\ \text{V}$ , $V_{SS} = 0\ \text{V}$ $V_S = 1\ \text{V}/10\ \text{V}$ , $V_D = 10\ \text{V}/1\ \text{V}$ ; see Figure 30
	$\pm 0.1$	$\pm 0.2$	$\pm 0.4$	nA max	
Drain Off Leakage, $I_D$ (Off)	$\pm 0.005$			nA typ	$V_S = 1\ \text{V}/10\ \text{V}$ , $V_D = 10\ \text{V}/1\ \text{V}$ ; see Figure 30
	$\pm 0.1$	$\pm 0.4$	$\pm 1.4$	nA max	
Channel On Leakage, $I_D$ (On), $I_S$ (On)	$\pm 0.01$			nA typ	$V_S = V_D = 1\ \text{V}/10\ \text{V}$ ; see Figure 27
	$\pm 0.2$	$\pm 0.5$	$\pm 1.4$	nA max	
<b>DIGITAL INPUTS</b>					
Input High Voltage, $V_{INH}$			2.0	V min	
Input Low Voltage, $V_{INL}$			0.8	V max	
Input Current, $I_{INL}$ or $I_{INH}$	0.002			$\mu\text{A}$ typ	$V_{IN} = V_{GND}$ or $V_{DD}$
			$\pm 0.1$	$\mu\text{A}$ max	
Digital Input Capacitance, $C_{IN}$	3			pF typ	

Parameter	25°C	−40°C to +85°C	−40°C to +125°C	Unit	Test Conditions/Comments		
DYNAMIC CHARACTERISTICS <sup>1</sup>							
Transition Time, t <sub>TRANSITION</sub>	210	330	380	ns typ	R <sub>L</sub> = 300 Ω, C <sub>L</sub> = 35 pF		
	270			ns max	V <sub>S</sub> = 8 V; see Figure 33		
t <sub>ON</sub> (EN)	215	345	400	ns typ	R <sub>L</sub> = 300 Ω, C <sub>L</sub> = 35 pF		
	275			ns max	V <sub>S</sub> = 8 V; see Figure 35		
t <sub>OFF</sub> (EN)	115	160	175	ns typ	R <sub>L</sub> = 300 Ω, C <sub>L</sub> = 35 pF		
	140			ns max	V <sub>S</sub> = 8 V; see Figure 35		
Break-Before-Make Time Delay, t <sub>D</sub>	135	70		ns typ	R <sub>L</sub> = 300 Ω, C <sub>L</sub> = 35 pF		
				ns min	V <sub>S1</sub> = V <sub>S2</sub> = 8 V; see Figure 34		
Charge Injection, Q <sub>INJ</sub>	0.3			pC typ	V <sub>S</sub> = 6 V, R <sub>S</sub> = 0 Ω, C <sub>L</sub> = 1 nF; see Figure 36		
Off Isolation	−90			dB typ	R <sub>L</sub> = 50 Ω, C <sub>L</sub> = 5 pF, f = 1 MHz; see Figure 31		
Channel-to-Channel Crosstalk	−90			dB typ	R <sub>L</sub> = 50 Ω, C <sub>L</sub> = 5 pF, f = 1 MHz; see Figure 29		
−3 dB Bandwidth					R <sub>L</sub> = 50 Ω, C <sub>L</sub> = 5 pF; see Figure 32		
ADG5208	60			MHz typ			
ADG5209	120			MHz typ			
Insertion Loss	−8.8			dB typ	R <sub>L</sub> = 50 Ω, C <sub>L</sub> = 5 pF, f = 1 MHz; see Figure 32		
C <sub>S</sub> (Off)	6			pF typ	V <sub>S</sub> = 6 V, f = 1 MHz		
C <sub>D</sub> (Off)							
ADG5208	56			pF typ	V <sub>S</sub> = 6 V, f = 1 MHz		
ADG5209	28			pF typ	V <sub>S</sub> = 6 V, f = 1 MHz		
C <sub>D</sub> (On), C <sub>S</sub> (On)							
ADG5208	63			pF typ	V <sub>S</sub> = 6 V, f = 1 MHz		
ADG5209	35			pF typ	V <sub>S</sub> = 6 V, f = 1 MHz		
POWER REQUIREMENTS							
I <sub>DD</sub>	40				65	μA typ	V <sub>DD</sub> = 13.2 V
	50	μA max	Digital inputs = 0 V or V <sub>DD</sub>				
V <sub>DD</sub>		V min/V max	GND = 0 V, V <sub>SS</sub> = 0 V				

<sup>1</sup> Guaranteed by design; not subject to production test.

### 36 V SINGLE SUPPLY

$V_{\text{DD}} = 36\ \text{V} \pm 10\%$ ,  $V_{\text{SS}} = 0\ \text{V}$ , GND = 0 V, unless otherwise noted.

Table 4.

Parameter	25°C	−40°C to +85°C	−40°C to +125°C	Unit	Test Conditions/Comments
<b>ANALOG SWITCH</b>					
Analogue Signal Range			0 V to $V_{\text{DD}}$	V	
On Resistance, $R_{\text{ON}}$	150	215	245	$\Omega\ \text{typ}$	$V_S = 0\ \text{V}$ to 30 V, $I_S = -1\ \text{mA}$ ; see Figure 28
On-Resistance Match Between Channels, $\Delta R_{\text{ON}}$	3.5			$\Omega\ \text{max}$ $\Omega\ \text{typ}$	$V_{\text{DD}} = 32.4\ \text{V}$ , $V_{\text{SS}} = 0\ \text{V}$ $V_S = 0\ \text{V}$ to 30 V, $I_S = -1\ \text{mA}$
On-Resistance Flatness, $R_{\text{FLAT}}(\text{ON})$	8 35 55	9 65	10 70	$\Omega\ \text{max}$ $\Omega\ \text{typ}$ $\Omega\ \text{max}$	$V_S = 0\ \text{V}$ to 30 V, $I_S = -1\ \text{mA}$
<b>LEAKAGE CURRENTS</b>					
Source Off Leakage, $I_S(\text{Off})$	$\pm 0.005$	$\pm 0.2$	$\pm 0.4$	nA typ	$V_{\text{DD}} = 39.6\ \text{V}$ , $V_{\text{SS}} = 0\ \text{V}$ $V_S = 1\ \text{V}/30\ \text{V}$ , $V_D = 30\ \text{V}/1\ \text{V}$ ; see Figure 30
	$\pm 0.1$			nA max	

Parameter	25°C	–40°C to +85°C	–40°C to +125°C	Unit	Test Conditions/Comments
Drain Off Leakage, $I_D$ (Off)	±0.005			nA typ	$V_S = 1\text{ V}/30\text{ V}$ , $V_D = 30\text{ V}/1\text{ V}$ ; see Figure 30
Channel On Leakage, $I_D$ (On), $I_S$ (On)	±0.1 ±0.01 ±0.2	±0.4 ±0.5	±1.4 ±1.4	nA max nA typ nA max	$V_S = V_D = 1\text{ V}/30\text{ V}$ ; see Figure 27
DIGITAL INPUTS					
Input High Voltage, $V_{INH}$			2.0	V min	$V_{IN} = V_{GND}$ or $V_{DD}$
Input Low Voltage, $V_{INL}$			0.8	V max	
Input Current, $I_{INL}$ or $I_{INH}$	0.002		±0.1	µA typ µA max	
Digital Input Capacitance, $C_{IN}$	3			pF typ	
DYNAMIC CHARACTERISTICS <sup>1</sup>					
Transition Time, $t_{TRANSITION}$	185 230	245	259	ns typ ns max	$R_L = 300\ \Omega$ , $C_L = 35\text{ pF}$ $V_S = 18\text{ V}$ ; see Figure 33
$t_{ON}$ (EN)	170 210			ns typ ns max	$R_L = 300\ \Omega$ , $C_L = 35\text{ pF}$ $V_S = 18\text{ V}$ ; see Figure 35
$t_{OFF}$ (EN)	125 180			ns typ ns max	$R_L = 300\ \Omega$ , $C_L = 35\text{ pF}$ $V_S = 18\text{ V}$ ; see Figure 35
Break-Before-Make Time Delay, $t_D$	70			ns typ ns min	$R_L = 300\ \Omega$ , $C_L = 35\text{ pF}$ $V_{S1} = V_{S2} = 18\text{ V}$ ; see Figure 34
Charge Injection, $Q_{INJ}$	0.4		35	pC typ	$V_S = 18\text{ V}$ , $R_S = 0\ \Omega$ , $C_L = 1\text{ nF}$ ; see Figure 36
Off Isolation	–90			dB typ	$R_L = 50\ \Omega$ , $C_L = 5\text{ pF}$ , $f = 1\text{ MHz}$ ; see Figure 31
Channel-to-Channel Crosstalk	–90			dB typ	$R_L = 50\ \Omega$ , $C_L = 5\text{ pF}$ , $f = 1\text{ MHz}$ ; see Figure 29
–3 dB Bandwidth					$R_L = 50\ \Omega$ , $C_L = 5\text{ pF}$ ; see Figure 32
ADG5208	65			MHz typ	
ADG5209	130			MHz typ	
Insertion Loss	–6			dB typ	$R_L = 50\ \Omega$ , $C_L = 5\text{ pF}$ , $f = 1\text{ MHz}$ ; see Figure 32
$C_S$ (Off)	5.5			pF typ	$V_S = 18\text{ V}$ , $f = 1\text{ MHz}$
$C_D$ (Off)					
ADG5208	51			pF typ	$V_S = 18\text{ V}$ , $f = 1\text{ MHz}$
ADG5209	25			pF typ	$V_S = 18\text{ V}$ , $f = 1\text{ MHz}$
$C_D$ (On), $C_S$ (On)					
ADG5208	57			pF typ	$V_S = 18\text{ V}$ , $f = 1\text{ MHz}$
ADG5209	32			pF typ	$V_S = 18\text{ V}$ , $f = 1\text{ MHz}$
POWER REQUIREMENTS					$V_{DD} = 39.6\text{ V}$
$I_{DD}$	80 100			µA typ µA max	Digital inputs = 0 V or $V_{DD}$
$V_{DD}$			130 9/40	V min/V max	$GND = 0\text{ V}$ , $V_{SS} = 0\text{ V}$

<sup>1</sup> Guaranteed by design; not subject to production test.

**CONTINUOUS CURRENT PER CHANNEL, Sx, D, OR Dx****Table 5. ADG5208**

Parameter	25°C	85°C	125°C	Unit
CONTINUOUS CURRENT, Sx OR D				
$V_{DD} = +15\text{ V}$ , $V_{SS} = -15\text{ V}$				
TSSOP ( $\theta_{JA} = 112.6^{\circ}\text{C/W}$ )	40	24	14.5	mA maximum
LFCSP ( $\theta_{JA} = 30.4^{\circ}\text{C/W}$ )	69	37	18	mA maximum
$V_{DD} = +20\text{ V}$ , $V_{SS} = -20\text{ V}$				
TSSOP ( $\theta_{JA} = 112.6^{\circ}\text{C/W}$ )	42	26.5	14.5	mA maximum
LFCSP ( $\theta_{JA} = 30.4^{\circ}\text{C/W}$ )	75	40	18	mA maximum
$V_{DD} = 12\text{ V}$ , $V_{SS} = 0\text{ V}$				
TSSOP ( $\theta_{JA} = 112.6^{\circ}\text{C/W}$ )	28	19	12	mA maximum
LFCSP ( $\theta_{JA} = 30.4^{\circ}\text{C/W}$ )	40	25	14.5	mA maximum
$V_{DD} = 36\text{ V}$ , $V_{SS} = 0\text{ V}$				
TSSOP ( $\theta_{JA} = 112.6^{\circ}\text{C/W}$ )	40	26	14.5	mA maximum
LFCSP ( $\theta_{JA} = 30.4^{\circ}\text{C/W}$ )	72	39	18	mA maximum

**Table 6. ADG5209**

Parameter	25°C	85°C	125°C	Unit
CONTINUOUS CURRENT, Sx OR Dx				
$V_{DD} = +15\text{ V}$ , $V_{SS} = -15\text{ V}$				
TSSOP ( $\theta_{JA} = 112.6^{\circ}\text{C/W}$ )	29	19	12	mA maximum
LFCSP ( $\theta_{JA} = 30.4^{\circ}\text{C/W}$ )	51	30	16	mA maximum
$V_{DD} = +20\text{ V}$ , $V_{SS} = -20\text{ V}$				
TSSOP ( $\theta_{JA} = 112.6^{\circ}\text{C/W}$ )	30	20	12.5	mA maximum
LFCSP ( $\theta_{JA} = 30.4^{\circ}\text{C/W}$ )	55	32	17	mA maximum
$V_{DD} = 12\text{ V}$ , $V_{SS} = 0\text{ V}$				
TSSOP ( $\theta_{JA} = 112.6^{\circ}\text{C/W}$ )	20	14	10	mA maximum
LFCSP ( $\theta_{JA} = 30.4^{\circ}\text{C/W}$ )	29	20	12.5	mA maximum
$V_{DD} = 36\text{ V}$ , $V_{SS} = 0\text{ V}$				
TSSOP ( $\theta_{JA} = 112.6^{\circ}\text{C/W}$ )	30	20	12.5	mA maximum
LFCSP ( $\theta_{JA} = 30.4^{\circ}\text{C/W}$ )	54	31	17	mA maximum



## ABSOLUTE MAXIMUM RATINGS

$T_A = 25^\circ\text{C}$ , unless otherwise noted.

Table 7.

Parameter	Rating
$V_{DD}$ to $V_{SS}$	48 V
$V_{DD}$ to GND	−0.3 V to +48 V
$V_{SS}$ to GND	+0.3 V to −48 V
Analog Inputs <sup>1</sup>	$V_{SS} - 0.3\text{ V}$ to $V_{DD} + 0.3\text{ V}$ or 30 mA, whichever occurs first
Digital Inputs <sup>1</sup>	$V_{SS} - 0.3\text{ V}$ to $V_{DD} + 0.3\text{ V}$ or 30 mA, whichever occurs first
Peak Current, $S_x$ , D, or $D_x$ Pins ADG5208 ADG5209	126 mA (pulsed at 1 ms, 10% duty cycle maximum) 92 mA (pulsed at 1 ms, 10% duty cycle maximum)
Continuous Current, $S_x$ , D, or $D_x$ Pins <sup>2</sup>	Data + 15%
Temperature Range	
Operating	−40°C to +125°C
Storage	−65°C to +150°C
Junction Temperature	150°C
Thermal Impedance, $\theta_{JA}$	
16-Lead TSSOP (4-Layer Board)	112.6°C/W
16-Lead LFCSP (4-Layer Board)	30.4°C/W
Reflow Soldering Peak Temperature, Pb Free	260(+0/−5)°C
HBM ESD	
I/O Port to Supplies	4 kV
I/O Port to I/O Port	1 kV
All Other Pins	4 kV

<sup>1</sup> Overvoltages at the  $A_x$ , EN,  $S_x$ , D, and  $D_x$  pins are clamped by internal diodes. Limit current to the maximum ratings given.

<sup>2</sup> See Table 5 and Table 6.

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Only one absolute maximum rating can be applied at any one time.

### ESD CAUTION



#### ESD (electrostatic discharge) sensitive device.

Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

## PIN CONFIGURATIONS AND FUNCTION DESCRIPTIONS

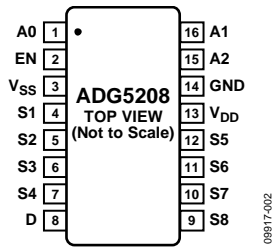
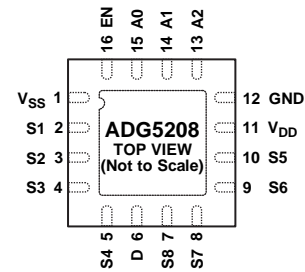


Figure 2. ADG5208 Pin Configuration (TSSOP)



NOTES  
1. THE EXPOSED PAD IS CONNECTED INTERNALLY. FOR INCREASED RELIABILITY OF THE SOLDER JOINTS AND MAXIMUM THERMAL CAPABILITY, IT IS RECOMMENDED THAT THE PAD BE SOLDERED TO THE SUBSTRATE,  $V_{SS}$ .

Figure 3. ADG5208 Pin Configuration (LFCSP)

Table 8. ADG5208 Pin Function Descriptions

Pin No.		Mnemonic	Description
TSSOP	LFCSP		
1	15	A0	Logic Control Input.
2	16	EN	Active High Digital Input. When low, the device is disabled and all switches are off. When high, the Ax logic inputs determine the on switches.
3	1	$V_{SS}$	Most Negative Power Supply Potential. In single-supply applications, this pin can be connected to ground.
4	2	S1	Source Terminal 1. This pin can be an input or an output.
5	3	S2	Source Terminal 2. This pin can be an input or an output.
6	4	S3	Source Terminal 3. This pin can be an input or an output.
7	5	S4	Source Terminal 4. This pin can be an input or an output.
8	6	D	Drain Terminal. This pin can be an input or an output.
9	7	S8	Source Terminal 8. This pin can be an input or an output.
10	8	S7	Source Terminal 7. This pin can be an input or an output.
11	9	S6	Source Terminal 6. This pin can be an input or an output.
12	10	S5	Source Terminal 5. This pin can be an input or an output.
13	11	$V_{DD}$	Most Positive Power Supply Potential.
14	12	GND	Ground (0 V) Reference.
15	13	A2	Logic Control Input.
16	14	A1	Logic Control Input.
	EP	Exposed Pad	The exposed pad is connected internally. For increased reliability of the solder joints and maximum thermal capability, it is recommended that the pad be soldered to the substrate, $V_{SS}$ .

Table 9. ADG5208 Truth Table

A2	A1	A0	EN	On Switch
X <sup>1</sup>	X <sup>1</sup>	X <sup>1</sup>	0	None
0	0	0	1	1
0	0	1	1	2
0	1	0	1	3
0	1	1	1	4
1	0	0	1	5
1	0	1	1	6
1	1	0	1	7
1	1	1	1	8

<sup>1</sup> X is don't care.

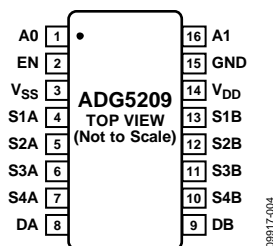
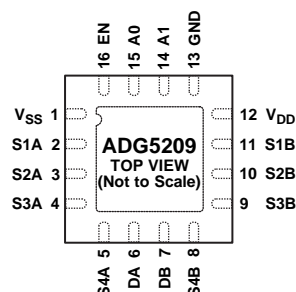


Figure 4. ADG5209 Pin Configuration (TSSOP)



NOTES  
1. THE EXPOSED PAD IS CONNECTED INTERNALLY. FOR INCREASED RELIABILITY OF THE SOLDER JOINTS AND MAXIMUM THERMAL CAPABILITY, IT IS RECOMMENDED THAT THE PAD BE SOLDERED TO THE SUBSTRATE,  $V_{SS}$ .

Figure 5. ADG5209 Pin Configuration (LFCSP)

Table 10. ADG5209 Pin Function Descriptions

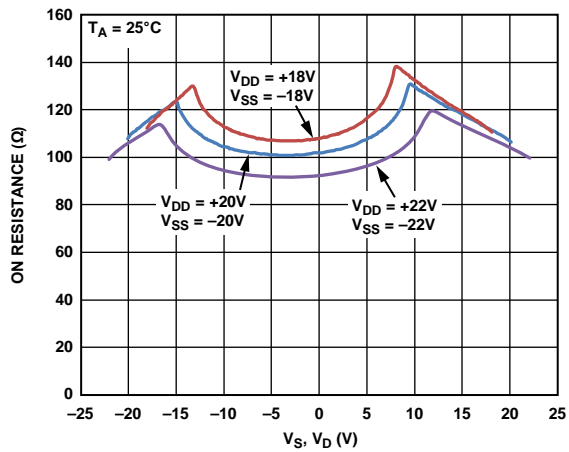
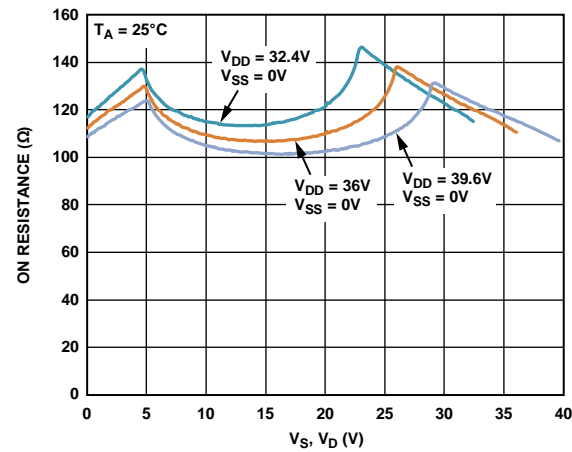
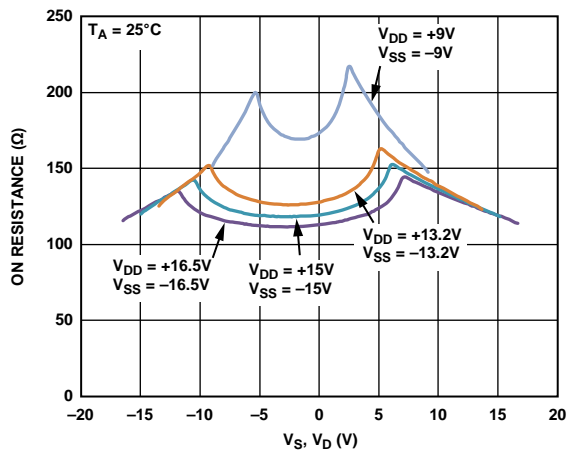
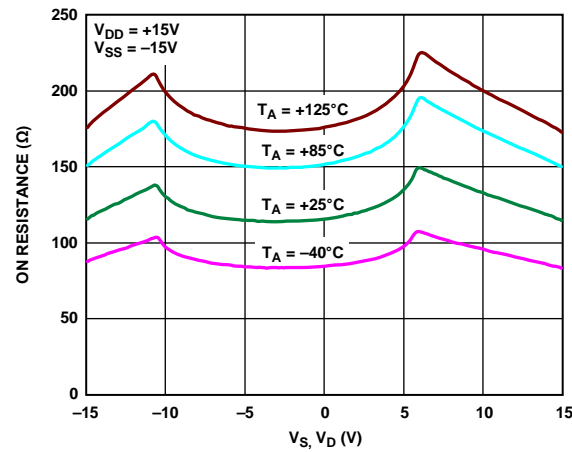
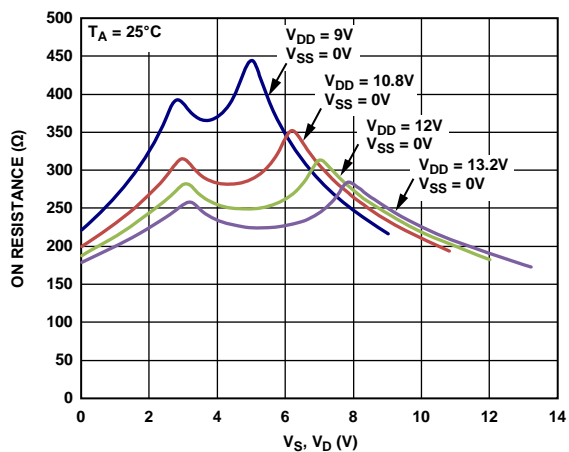
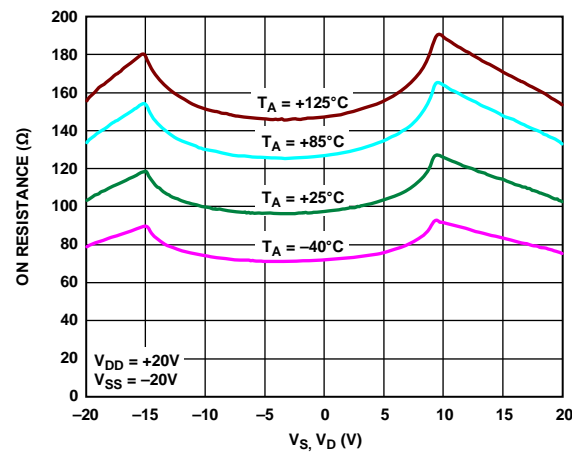
Pin No.		Mnemonic	Description
TSSOP	LFCSP		
1	15	A0	Logic Control Input.
2	16	EN	Active High Digital Input. When low, the device is disabled and all switches are off. When high, Ax logic inputs determine the on switches.
3	1	$V_{SS}$	Most Negative Power Supply Potential. In single-supply applications, this pin can be connected to ground.
4	2	S1A	Source Terminal 1A. This pin can be an input or an output.
5	3	S2A	Source Terminal 2A. This pin can be an input or an output.
6	4	S3A	Source Terminal 3A. This pin can be an input or an output.
7	5	S4A	Source Terminal 4A. This pin can be an input or an output.
8	6	DA	Drain Terminal A. This pin can be an input or an output.
9	7	DB	Drain Terminal B. This pin can be an input or an output.
10	8	S4B	Source Terminal 4B. This pin can be an input or an output.
11	9	S3B	Source Terminal 3B. This pin can be an input or an output.
12	10	S2B	Source Terminal 2B. This pin can be an input or an output.
13	11	S1B	Source Terminal 1B. This pin can be an input or an output.
14	12	$V_{DD}$	Most Positive Power Supply Potential.
15	13	GND	Ground (0 V) Reference.
16	14	A1	Logic Control Input.
	EP	Exposed Pad	The exposed pad is connected internally. For increased reliability of the solder joints and maximum thermal capability, it is recommended that the pad be soldered to the substrate, $V_{SS}$ .

Table 11. ADG5209 Truth Table

A1	A0	EN	On Switch Pair
X <sup>1</sup>	X <sup>1</sup>	0	None
0	0	1	1
0	1	1	2
1	0	1	3
1	1	1	4

<sup>1</sup> X is don't care.

## TYPICAL PERFORMANCE CHARACTERISTICS

Figure 6.  $R_{ON}$  as a Function of  $V_S$ ,  $V_D$  ( $\pm 20$  V Dual Supply)Figure 9.  $R_{ON}$  as a Function of  $V_S$ ,  $V_D$  (36 V Single Supply)Figure 7.  $R_{ON}$  as a Function of  $V_S$ ,  $V_D$  ( $\pm 15$  V Dual Supply)Figure 10.  $R_{ON}$  as a Function of  $V_S$ ,  $V_D$  for Different Temperatures,  $\pm 15$  V Dual SupplyFigure 8.  $R_{ON}$  as a Function of  $V_S$ ,  $V_D$  (12 V Single Supply)Figure 11.  $R_{ON}$  as a Function of  $V_S$ ,  $V_D$  for Different Temperatures,  $\pm 20$  V Dual Supply

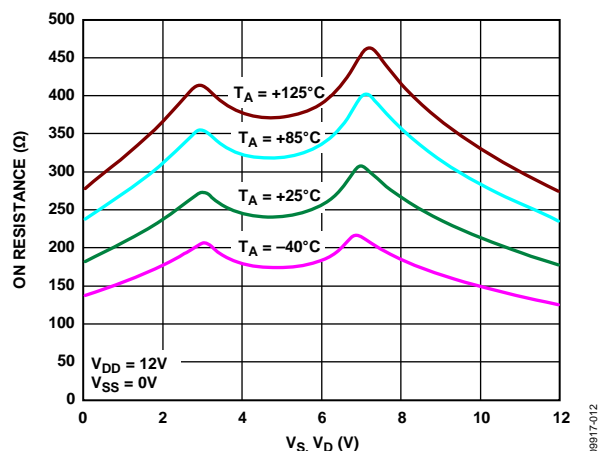


Figure 12.  $R_{ON}$  as a Function of  $V_S, V_D$  for Different Temperatures, 12 V Single Supply

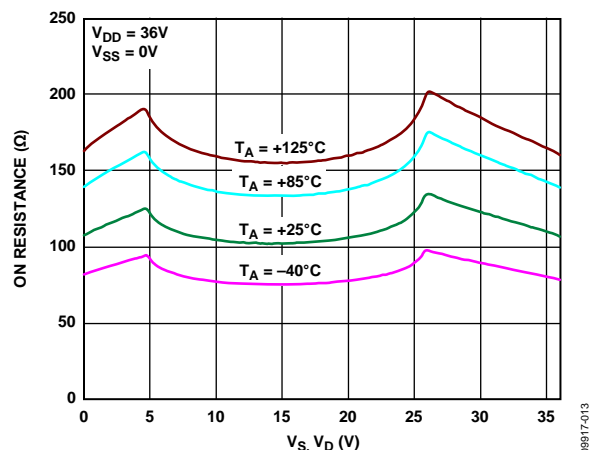


Figure 13.  $R_{ON}$  as a Function of  $V_S, V_D$  for Different Temperatures, 36 V Single Supply

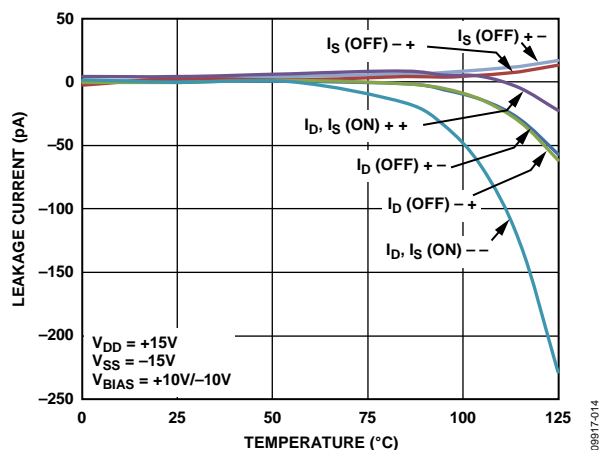


Figure 14. Leakage Currents vs. Temperature,  $\pm 15\text{V}$  Dual Supply

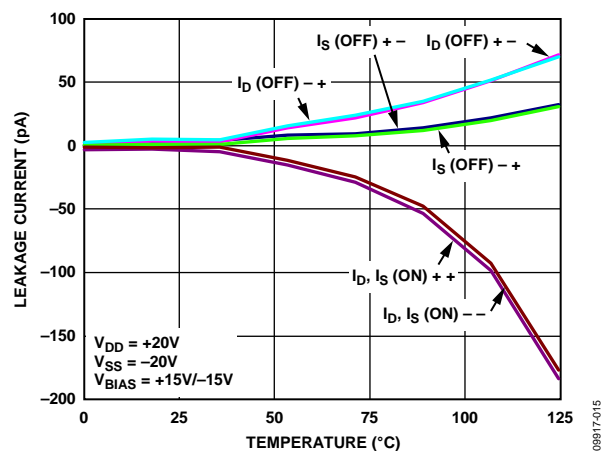


Figure 15. Leakage Currents vs. Temperature,  $\pm 20\text{V}$  Dual Supply

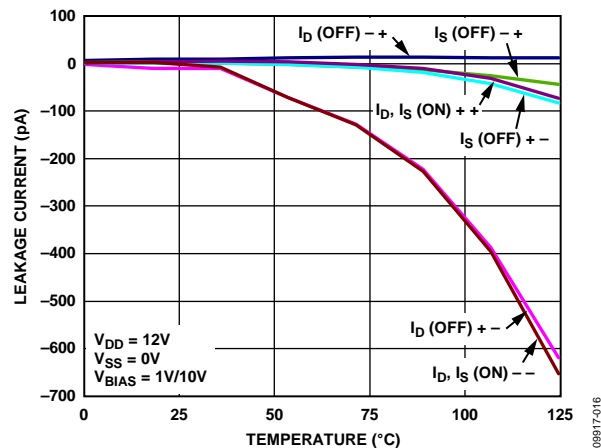


Figure 16. Leakage Currents vs. Temperature, 12 V Single Supply

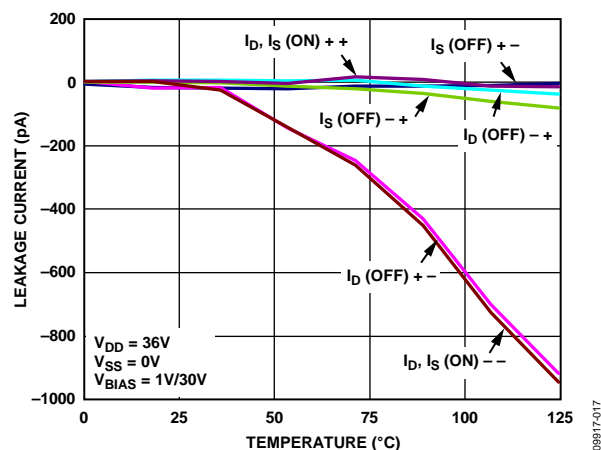


Figure 17. Leakage Currents vs. Temperature, 36 V Single Supply

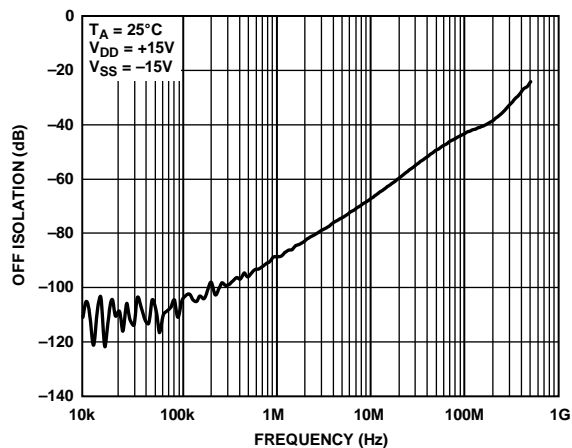


Figure 18. Off Isolation vs. Frequency, ±15 V Dual Supply

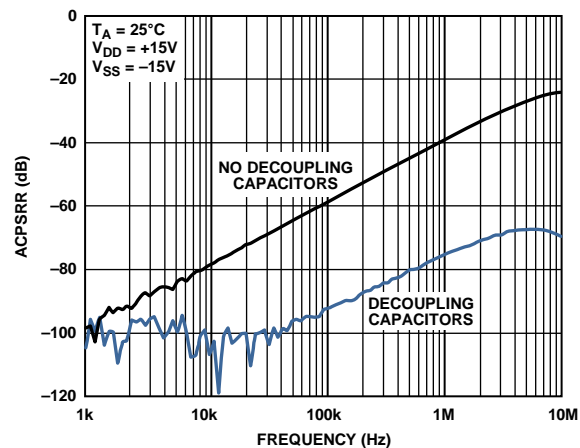


Figure 21. ACPSRR vs. Frequency, ±15 V Dual Supply

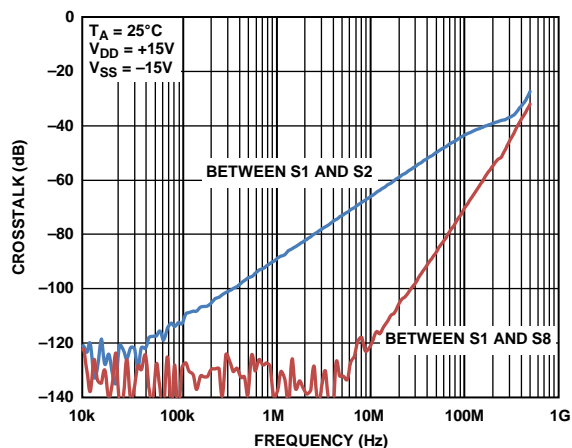


Figure 19. Crosstalk vs. Frequency, ±15 V Dual Supply

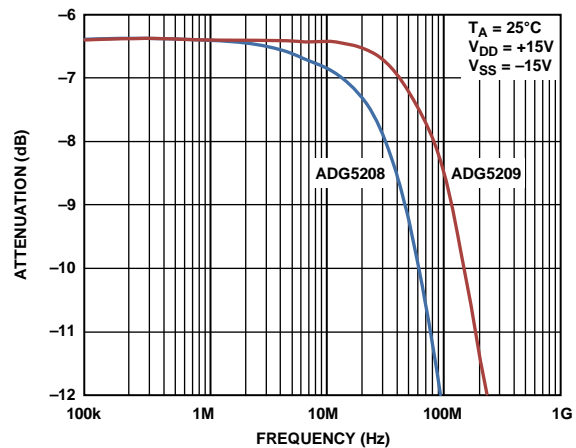


Figure 22. Bandwidth

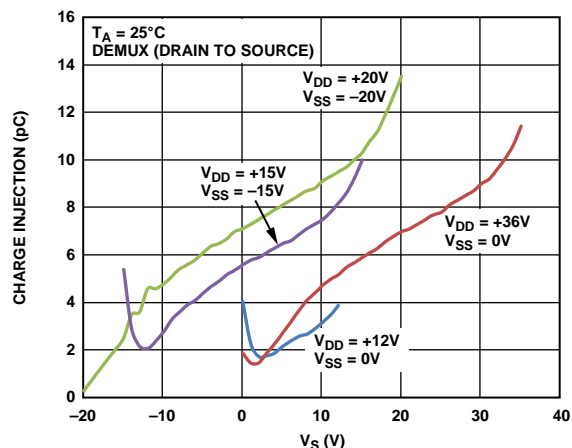


Figure 20. Charge Injection vs. Source Voltage, Drain to Source

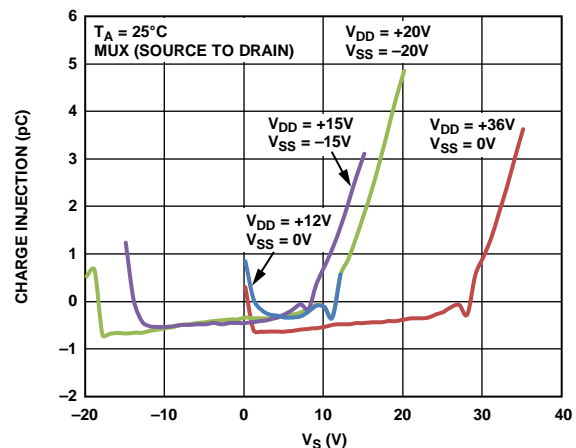
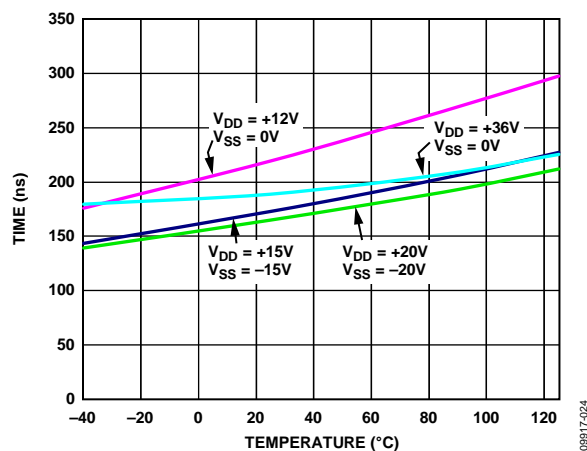
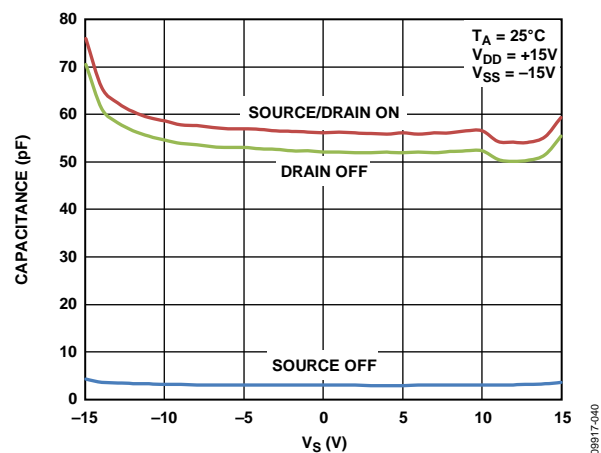
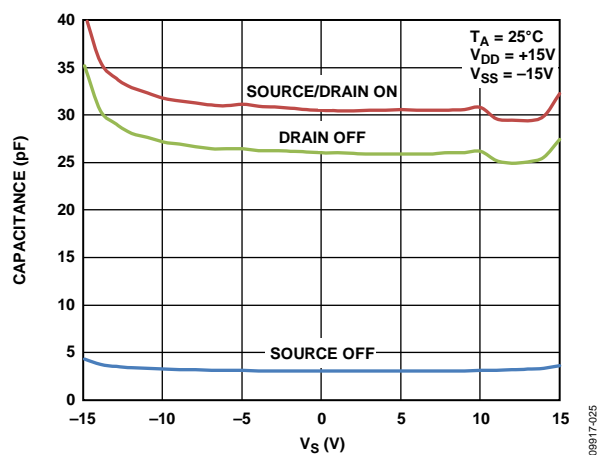


Figure 23. Charge Injection vs. Source Voltage, Source to Drain

Figure 24.  $t_{\text{TRANSITION}}$  Times vs. TemperatureFigure 26. ADG5208 Capacitance vs. Source Voltage,  $\pm 15$  V Dual SupplyFigure 25. ADG5209 Capacitance vs. Source Voltage,  $\pm 15$  V Dual Supply

# TEST CIRCUITS

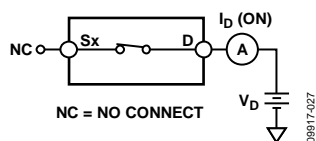


Figure 27. On Leakage

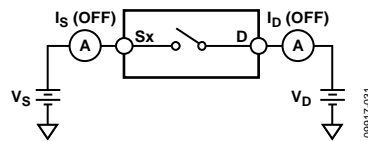


Figure 30. Off Leakage

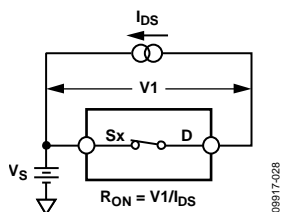


Figure 28. On Resistance

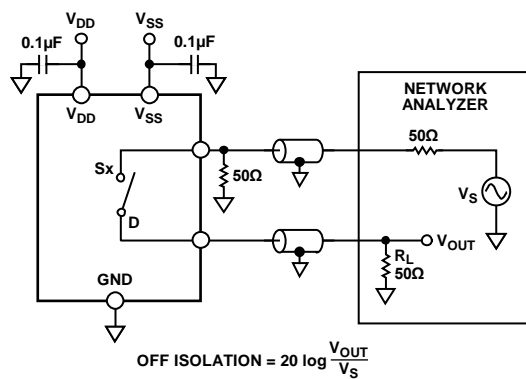


Figure 31. Off Isolation

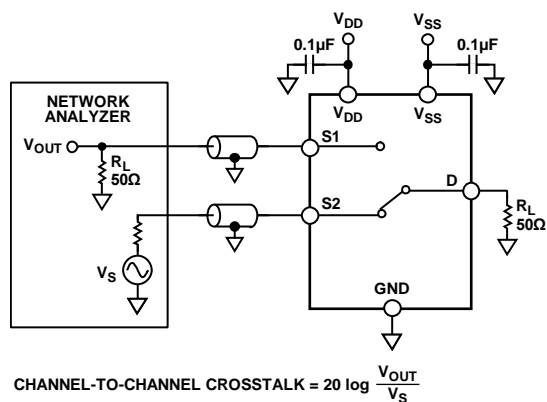


Figure 29. Channel-to-Channel Crosstalk

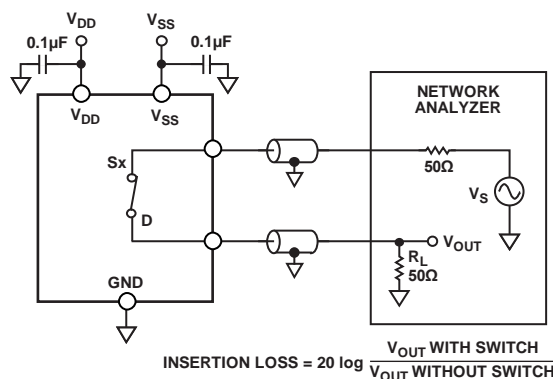
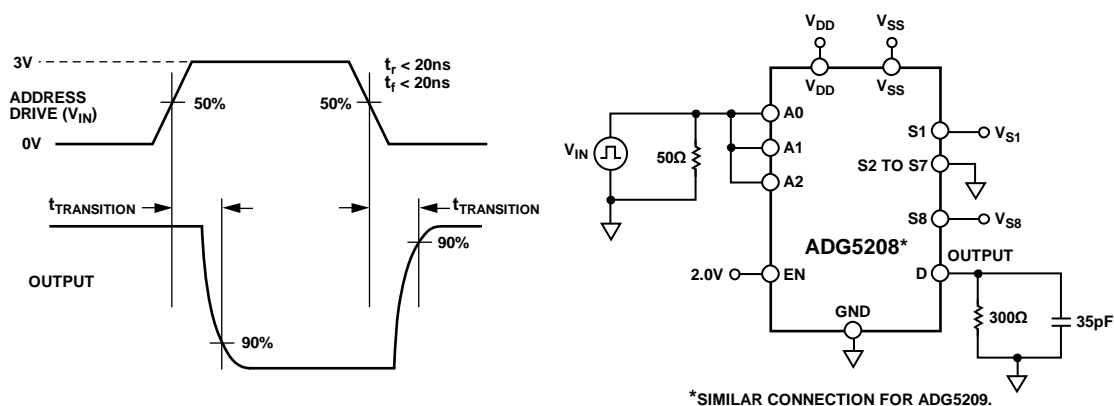
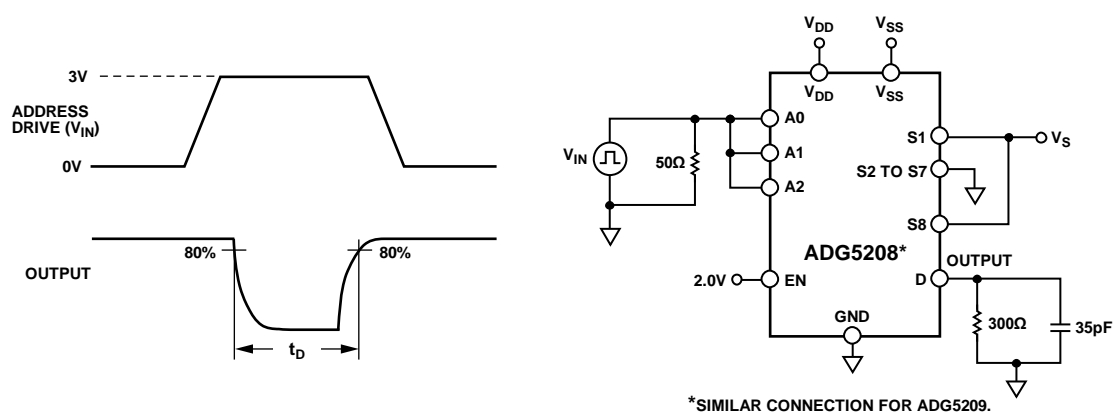
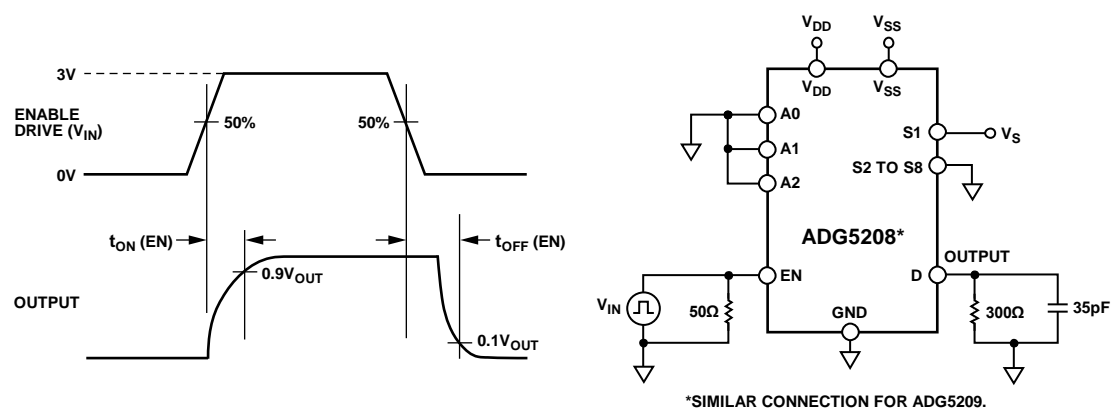


Figure 32. Bandwidth



Figure 33. Address to Output Switching Times,  $t_{\text{TRANSITION}}$ Figure 34. Break-Before-Make Time Delay,  $t_D$ Figure 35. Enable Delay,  $t_{\text{ON}}(\text{EN})$ ,  $t_{\text{OFF}}(\text{EN})$

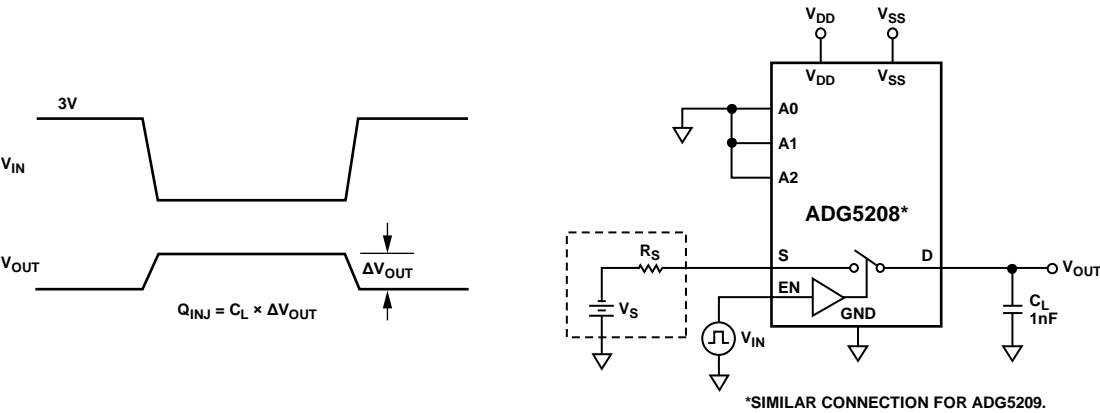


Figure 36. Charge Injection

06917-437

## TERMINOLOGY

### **I<sub>DD</sub>**

I<sub>DD</sub> represents the positive supply current.

### **I<sub>SS</sub>**

I<sub>SS</sub> represents the negative supply current.

### **V<sub>D</sub>, V<sub>S</sub>**

V<sub>D</sub> and V<sub>S</sub> represent the analog voltage on Terminal D and Terminal S, respectively.

### **R<sub>ON</sub>**

R<sub>ON</sub> is the ohmic resistance between Terminal D and Terminal S.

### **ΔR<sub>ON</sub>**

ΔR<sub>ON</sub> represents the difference between the R<sub>ON</sub> of any two channels.

### **R<sub>FLAT (ON)</sub>**

Flatness that is defined as the difference between the maximum and minimum value of on resistance measured over the specified analog signal range is represented by R<sub>FLAT (ON)</sub>.

### **I<sub>S</sub> (Off)**

I<sub>S</sub> (Off) is the source leakage current with the switch off.

### **I<sub>D</sub> (Off)**

I<sub>D</sub> (Off) is the drain leakage current with the switch off.

### **I<sub>D</sub> (On), I<sub>S</sub> (On)**

I<sub>D</sub> (On) and I<sub>S</sub> (On) represent the channel leakage currents with the switch on.

### **V<sub>INL</sub>**

V<sub>INL</sub> is the maximum input voltage for Logic 0.

### **V<sub>INH</sub>**

V<sub>INH</sub> is the minimum input voltage for Logic 1.

### **I<sub>INL</sub>, I<sub>INH</sub>**

I<sub>INL</sub> and I<sub>INH</sub> represent the low and high input currents of the digital inputs.

### **C<sub>D</sub> (Off)**

C<sub>D</sub> (Off) represents the off switch drain capacitance, which is measured with reference to ground.

### **C<sub>S</sub> (Off)**

C<sub>S</sub> (Off) represents the off switch source capacitance, which is measured with reference to ground.

### **C<sub>D</sub> (On), C<sub>S</sub> (On)**

C<sub>D</sub> (On) and C<sub>S</sub> (On) represent on switch capacitances, which are measured with reference to ground.

### **C<sub>IN</sub>**

C<sub>IN</sub> represents digital input capacitance.

### **t<sub>ON</sub> (EN)**

t<sub>ON</sub> (EN) represents the delay time between the 50% and 90% points of the digital input and switch on condition.

### **t<sub>OFF</sub> (EN)**

t<sub>OFF</sub> (EN) represents the delay time between the 50% and 90% points of the digital input and switch off condition.

### **t<sub>TRANSITION</sub>**

t<sub>TRANSITION</sub> represents the delay time between the 50% and 90% points of the digital inputs and the switch on condition when switching from one address state to another.

### **Break-Before-Make Time Delay (t<sub>D</sub>)**

t<sub>D</sub> represents the off time measured between the 80% point of both switches when switching from one address state to another.

### **Off Isolation**

Off isolation is a measure of unwanted signal coupling through an off channel.

### **Charge Injection**

Charge injection is a measure of the glitch impulse transferred from the digital input to the analog output during switching.

### **Crosstalk**

Crosstalk is a measure of unwanted signal that is coupled through from one channel to another as a result of parasitic capacitance.

### **Bandwidth**

Bandwidth is the frequency at which the output is attenuated by 3 dB.

### **On Response**

On response is the frequency response of the on switch.

### **AC Power Supply Rejection Ratio (ACPSRR)**

ACPSRR is a measure of the ability of a device to avoid coupling noise and spurious signals that appear on the supply voltage pin to the output of the switch. The dc voltage on the device is modulated by a sine wave of 0.62 V p-p. The ratio of the amplitude of signal on the output to the amplitude of the modulation is the ACPSRR.

## TRENCH ISOLATION

In the [ADG5208/ADG5209](#), an insulating oxide layer (trench) is placed between the NMOS and the PMOS transistors of each CMOS switch. Parasitic junctions, which occur between the transistors in junction isolated switches, are eliminated, and the result is a completely latch-up proof switch.

In junction isolation, the N and P wells of the PMOS and NMOS transistors form a diode that is reverse-biased under normal operation. However, during overvoltage conditions, this diode can become forward-biased. A silicon controlled rectifier (SCR) type circuit is formed by the two transistors, causing a significant amplification of the current that, in turn, leads to latch-up. With trench isolation, this diode is removed, and the result is a latch-up proof switch.

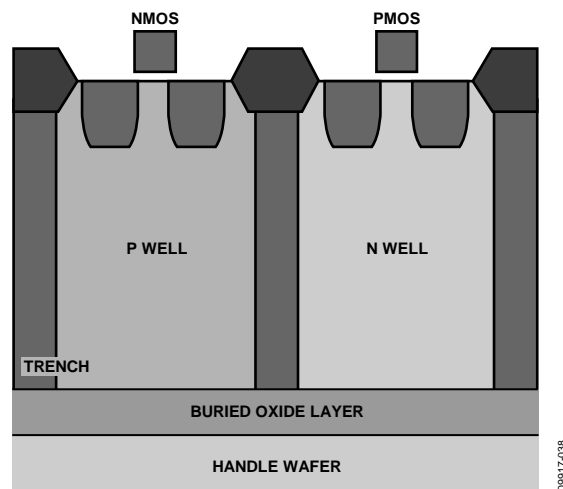
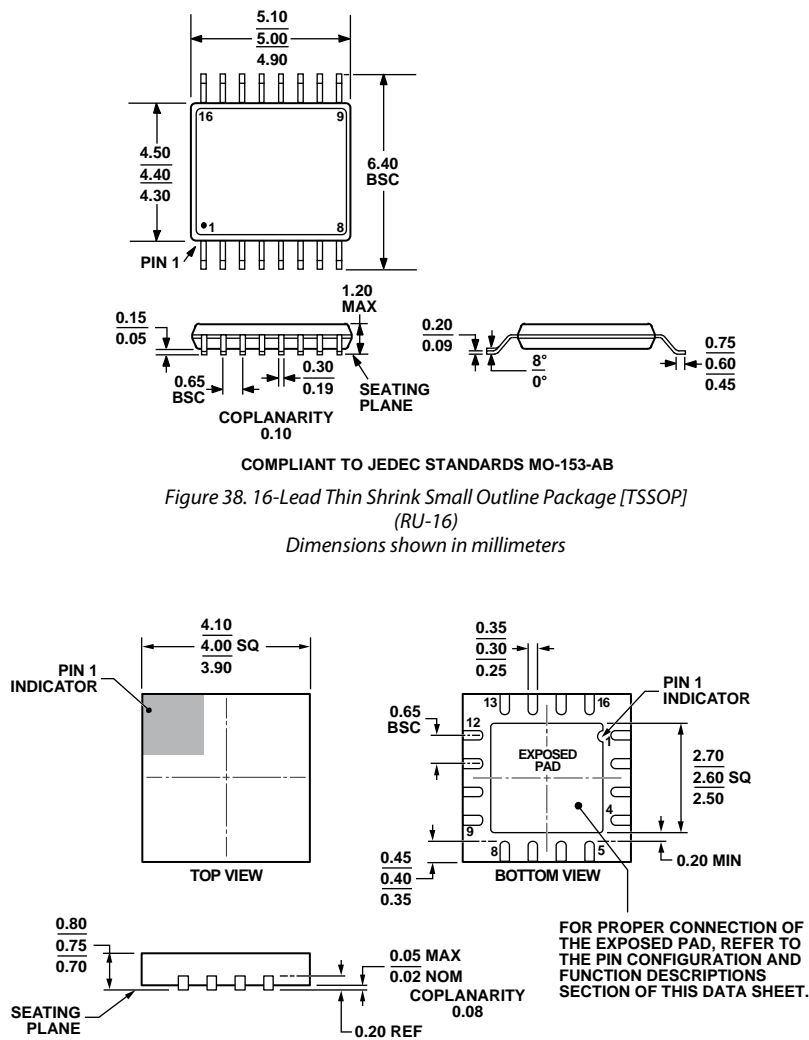


Figure 37. Trench Isolation

## APPLICATIONS INFORMATION

The ADG52xx family of switches and multiplexers provides a robust solution for instrumentation, industrial, automotive, aerospace, and other harsh environments that are prone to latch-up, which is an undesirable high current state that can lead to device failure and persist until the power supply is turned off. The [ADG5208/ADG5209](#) high voltage switches allow single-supply operation from 9 V to 40 V and dual-supply operation from  $\pm 9$  V to  $\pm 22$  V.

## OUTLINE DIMENSIONS



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## ORDERING GUIDE

Model <sup>1</sup>	Temperature Range	Package Description	Package Option
ADG5208BRUZ	−40°C to +125°C	16-Lead Thin Shrink Small Outline Package [TSSOP]	RU-16
ADG5208BRUZ-RL7	−40°C to +125°C	16-Lead Thin Shrink Small Outline Package [TSSOP]	RU-16
ADG5208BCPZ-RL7	−40°C to +125°C	16-Lead Lead Frame Chip Scale Package [LFCSP_WQ]	CP-16-17
ADG5209BCPZ-RL7	−40°C to +125°C	16-Lead Lead Frame Chip Scale Package [LFCSP_WQ]	CP-16-17
ADG5209BRUZ	−40°C to +125°C	16-Lead Thin Shrink Small Outline Package [TSSOP]	RU-16
ADG5209BRUZ-RL7	−40°C to +125°C	16-Lead Thin Shrink Small Outline Package [TSSOP]	RU-16

<sup>1</sup> Z = RoHS Compliant Part.

## NOTES

**NOTES**